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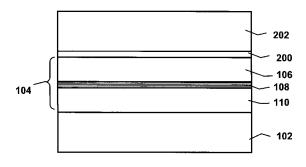


FIG. 4A

(57) Abstract: Techniques for fabricating contacts on inverted configuration surfaces of GaN layers of semiconductor devices are provided. An n-doped GaN layer may be formed with a surface exposed by removing a substrate on which the n-doped GaN layer was formed. The crystal structure of such a surface may have a significantly different configuration than the surface of an as-deposited p-doped GaN layer.



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Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) PubWEST(USPT,PGPB,EPAB,JPAB); Google Patents, Google Scholar Search terms: LED, GaN, substrate, remove, n-doped, p-doped, contact, electrode, metal, Al, AlTi, AlSi, AlCu, AlNi, Sn, Zn, Mg, Hf, W, Ta, Co,Vd, Mo, vertical light emitting diode, multi-quantum well, sapphire			
C. DOCUMENTS CONSIDERED TO BE RELEVANT			
Category*	Citation of document, with indication, where a		Relevant to claim No.
X 	US 2004/0209402 A1 (Chai et al.) 21 October 2004 (21.10.2004), Figs 2, 3, 6-9; paras [0031]- [0033], [0057], [0059], [0070], [0072],]0073], [0124], [0125]		1, 2, 4-6
Y			3, 7-10
Y	US 2004/0166599 A1 (Ishida) 26 August 2004 (26.08.2004), para [0017]		3, 7, 10
Υ	US 2006/0154392 A1 (Tran et al.) 13 July 2006 (13.07.2006), Figs 1, 3; paras [0021], [0027]		8-10
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